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## Sunter et al.

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# (54) BOUNDARY SCAN WITH STROBED PAD DRIVER ENABLE

(75) Inventors: **Stephen K. Sunter**, Nepean (CA);

Pièrre Gauthier, Gatineau (CA);

Benoit Nadeau-Dostie, Gatineau (CA)

(73) Assignee: LogicVision, Inc., San Jose, CA (US)

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## Related U.S. Application Data

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- (51) Int. Cl. G01R 31/28 (2006.01)

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Primary Examiner—Albert Decady Assistant Examiner—Steve Nguyen (74) Attorney, Agent, or Firm—Eugene E. Prouix

# (57) ABSTRACT

A circuit and a method are provided for testing the enable function of Boundary Scan Register bits that control the driver of unconnected I/O pins of an 1149.1-compliant IC during the IC's reduced pin-count access manufacturing test, and to test the connections to these pins during the test of a circuit board containing the IC, without causing excessive current if a pin is inadvertently short circuited.

### 7 Claims, 10 Drawing Sheets

